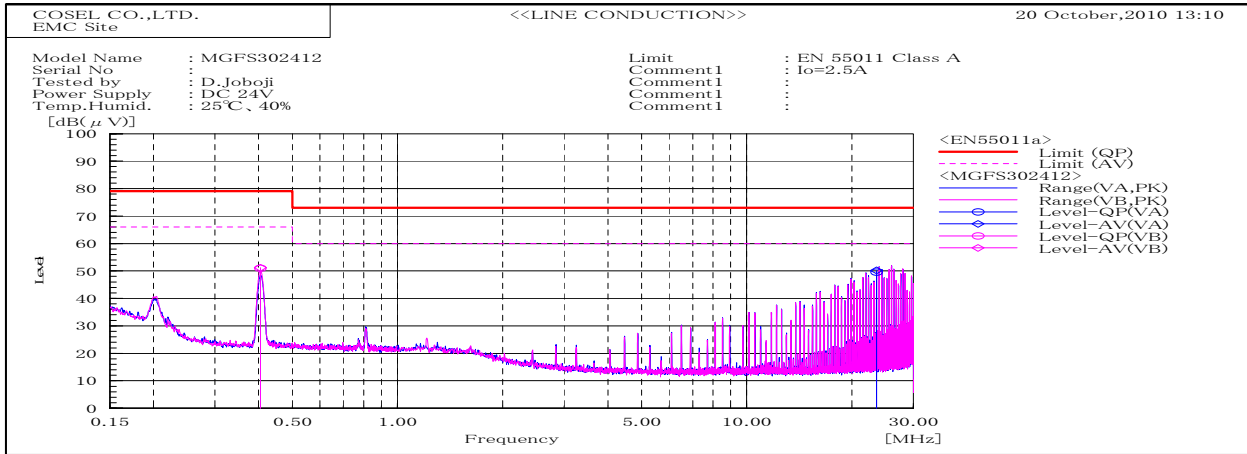
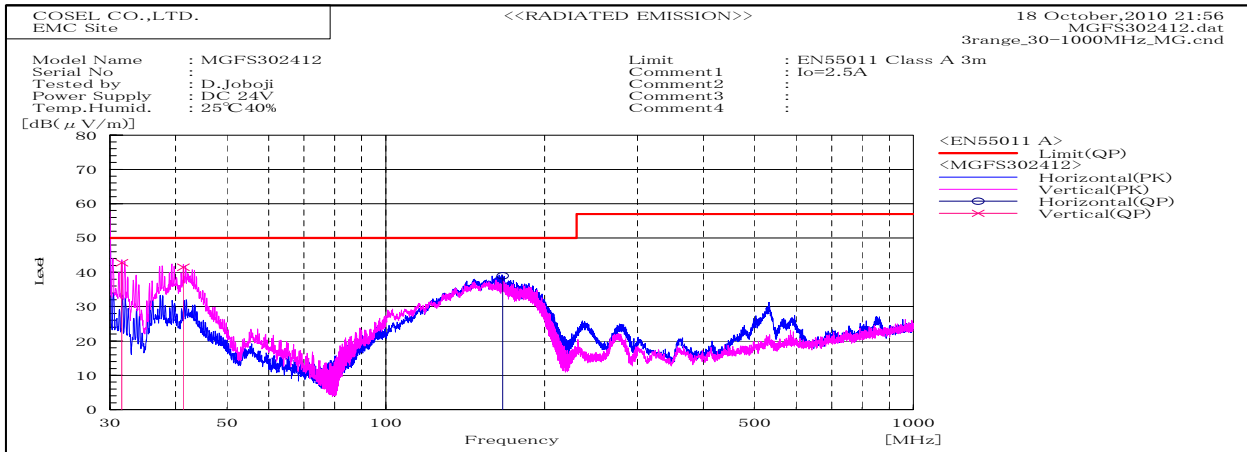


DATA SHEET		Date	20-Oct-10
Model	MGFS302412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Joboji



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.40506		VB	41	41.2	10	51	51.2	79	66	28	14.8	Pass	
23.51835		VA	38.7	39.3	10.9	49.6	50.2	73	60	23.4	9.8	Pass	

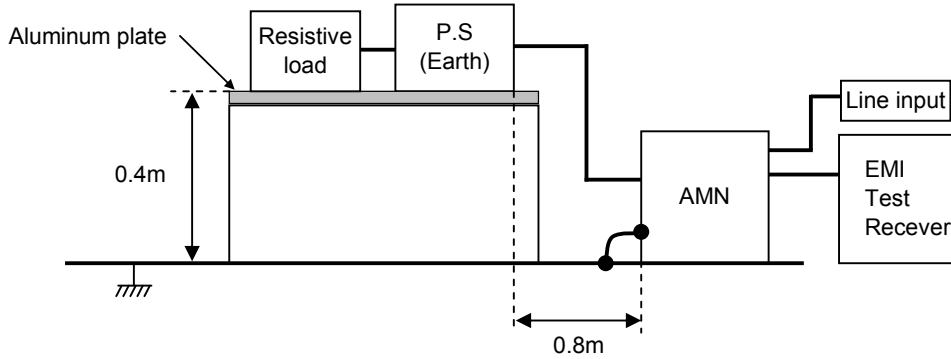


Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP						
31.616	V	Stable	57.1	-14.3	42.8	50	7.2	Pass	106	317			
41.345	V	Stable	60.8	-19.3	41.5	50	8.5	Pass	108	96			
166.591	H	Stable	60.6	-21.6	39	50	11	Pass	153	193			

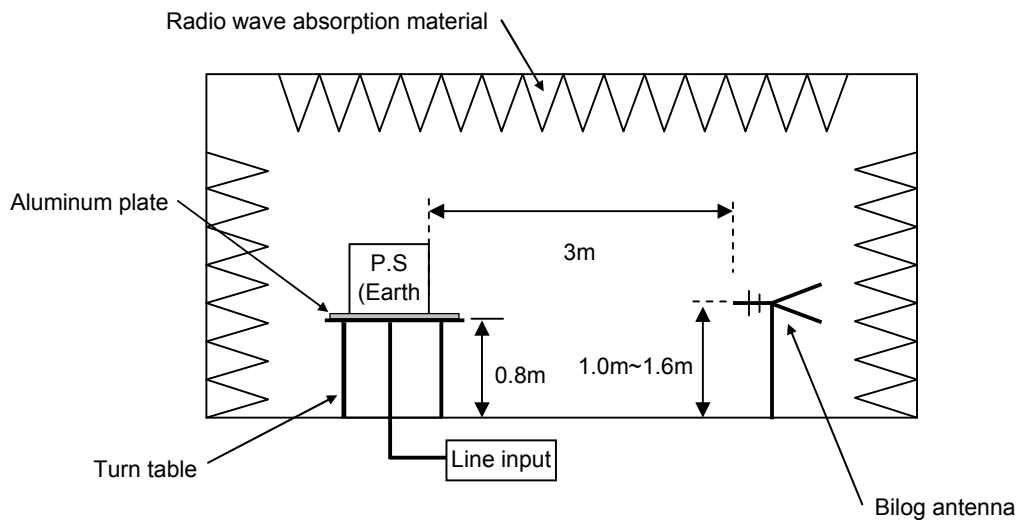
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission



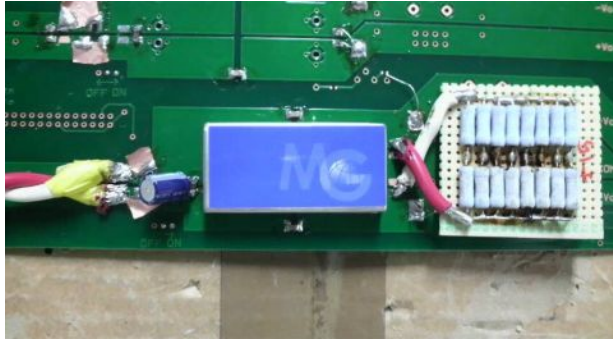


Conditions

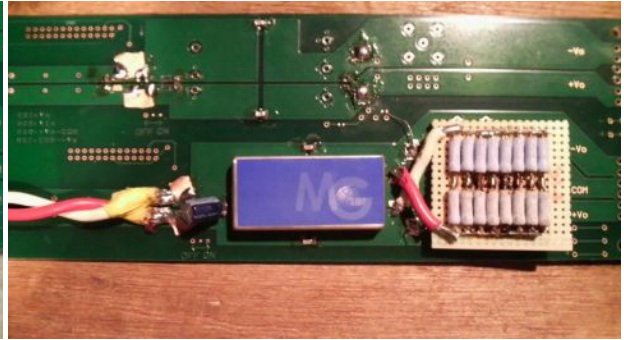
Test : EMI
 Model Name : MGFS3024□□/MGFW3024□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

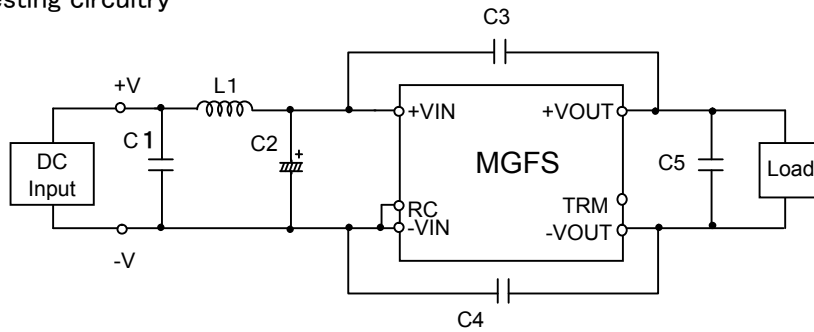


Fig.1 Testing circuitry 1

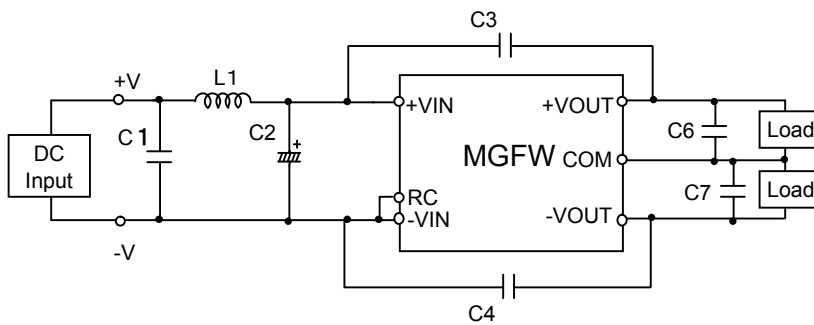


Fig.2 Testing circuitry 2

L1	: 0.6uH	CI8C-0R6	(KORIN ELECTRONICS)
C1	: 50V 4.7 μ F	Ceramic Capacitor	
C2	: 50V 100 μ F	Electrolytic Capacitor	
C3,C4	: 2kV 1000pF	Ceramic Capacitor	
C5,C6,C7	: 25V 22 μ F	Ceramic Capacitor	